Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	9600
Number of Logic Elements/Cells	43200
Total RAM Bits	655360
Number of I/O	404
Number of Gates	2541952
Voltage - Supply	1.71V ~ 1.89V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	560-LBGA Exposed Pad, Metal
Supplier Device Package	560-MBGA (42.5x42.5)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv2000e-6bg560i

Table 1: **Virtex-E Field-Programmable Gate Array Family Members**

Device	System Gates	Logic Gates	CLB Array	Logic Cells	Differential I/O Pairs	User I/O	BlockRAM Bits	Distributed RAM Bits
XCV50E	71,693	20,736	16 x 24	1,728	83	176	65,536	24,576
XCV100E	128,236	32,400	20 x 30	2,700	83	196	81,920	38,400
XCV200E	306,393	63,504	28 x 42	5,292	119	284	114,688	75,264
XCV300E	411,955	82,944	32 x 48	6,912	137	316	131,072	98,304
XCV400E	569,952	129,600	40 x 60	10,800	183	404	163,840	153,600
XCV600E	985,882	186,624	48 x 72	15,552	247	512	294,912	221,184
XCV1000E	1,569,178	331,776	64 x 96	27,648	281	660	393,216	393,216
XCV1600E	2,188,742	419,904	72 x 108	34,992	344	724	589,824	497,664
XCV2000E	2,541,952	518,400	80 x 120	43,200	344	804	655,360	614,400
XCV2600E	3,263,755	685,584	92 x 138	57,132	344	804	753,664	812,544
XCV3200E	4,074,387	876,096	104 x 156	73,008	344	804	851,968	1,038,336

Virtex-E Compared to Virtex Devices

The Virtex-E family offers up to 43,200 logic cells in devices up to 30% faster than the Virtex family.

I/O performance is increased to 622 Mb/s using Source Synchronous data transmission architectures and synchronous system performance up to 240 MHz using singled-ended SelectI/O technology. Additional I/O standards are supported, notably LVPECL, LVDS, and BLVDS, which use two pins per signal. Almost all signal pins can be used for these new standards.

Virtex-E devices have up to 640 Kb of faster (250 MHz) block SelectRAM, but the individual RAMs are the same size and structure as in the Virtex family. They also have eight DLLs instead of the four in Virtex devices. Each individual DLL is slightly improved with easier clock mirroring and 4x frequency multiplication.

V_{CCINT}, the supply voltage for the internal logic and memory, is 1.8 V, instead of 2.5 V for Virtex devices. Advanced processing and 0.18 µm design rules have resulted in smaller dice, faster speed, and lower power consumption.

I/O pins are 3 V tolerant, and can be 5 V tolerant with an external 100 Ω resistor. PCI 5 V is not supported. With the addition of appropriate external resistors, any pin can tolerate any voltage desired.

Banking rules are different. With Virtex devices, all input buffers are powered by V_{CCINT}. With Virtex-E devices, the LVTTL, LVCMOS2, and PCI input buffers are powered by the I/O supply voltage V_{CCO}.

The Virtex-E family is not bitstream-compatible with the Virtex family, but Virtex designs can be compiled into equivalent Virtex-E devices.

The same device in the same package for the Virtex-E and Virtex families are pin-compatible with some minor exceptions. See the data sheet pinout section for details.

General Description

The Virtex-E FPGA family delivers high-performance, high-capacity programmable logic solutions. Dramatic increases in silicon efficiency result from optimizing the new architecture for place-and-route efficiency and exploiting an aggressive 6-layer metal 0.18 µm CMOS process. These advances make Virtex-E FPGAs powerful and flexible alternatives to mask-programmed gate arrays. The Virtex-E family includes the nine members in Table 1.

Building on experience gained from Virtex FPGAs, the Virtex-E family is an evolutionary step forward in programmable logic design. Combining a wide variety of programmable system features, a rich hierarchy of fast, flexible interconnect resources, and advanced process technology, the Virtex-E family delivers a high-speed and high-capacity programmable logic solution that enhances design flexibility while reducing time-to-market.

Virtex-E Architecture

Virtex-E devices feature a flexible, regular architecture that comprises an array of configurable logic blocks (CLBs) surrounded by programmable input/output blocks (IOBs), all interconnected by a rich hierarchy of fast, versatile routing

Table 1: **Supported I/O Standards**

I/O Standard	Output V_{CCO}	Input V_{CCO}	Input V_{REF}	Board Termination Voltage (V_{TT})
LVTTL	3.3	3.3	N/A	N/A
LVCMOS2	2.5	2.5	N/A	N/A
LVCMOS18	1.8	1.8	N/A	N/A
SSTL3 I & II	3.3	N/A	1.50	1.50
SSTL2 I & II	2.5	N/A	1.25	1.25
GTL	N/A	N/A	0.80	1.20
GTL+	N/A	N/A	1.0	1.50
HSTL I	1.5	N/A	0.75	0.75
HSTL III & IV	1.5	N/A	0.90	1.50
CTT	3.3	N/A	1.50	1.50
AGP-2X	3.3	N/A	1.32	N/A
PCI33_3	3.3	3.3	N/A	N/A
PCI66_3	3.3	3.3	N/A	N/A
BLVDS & LVDS	2.5	N/A	N/A	N/A
LVPECL	3.3	N/A	N/A	N/A

In addition to the CLK and CE control signals, the three flip-flops share a Set/Reset (SR). For each flip-flop, this signal can be independently configured as a synchronous Set, a synchronous Reset, an asynchronous Preset, or an asynchronous Clear.

The output buffer and all of the IOB control signals have independent polarity controls.

All pads are protected against damage from electrostatic discharge (ESD) and from over-voltage transients. After configuration, clamping diodes are connected to V_{CCO} with the exception of LVCMOS18, LVCMOS25, GTL, GTL+, LVDS, and LVPECL.

Optional pull-up, pull-down and weak-keeper circuits are attached to each pad. Prior to configuration all outputs not involved in configuration are forced into their high-impedance state. The pull-down resistors and the weak-keeper circuits are inactive, but I/Os can optionally be pulled up.

The activation of pull-up resistors prior to configuration is controlled on a global basis by the configuration mode pins. If the pull-up resistors are not activated, all the pins are in a high-impedance state. Consequently, external pull-up or pull-down resistors must be provided on pins required to be at a well-defined logic level prior to configuration.

All Virtex-E IOBs support IEEE 1149.1-compatible Boundary Scan testing.

Input Path

The Virtex-E IOB input path routes the input signal directly to internal logic and/ or through an optional input flip-flop.

An optional delay element at the D-input of this flip-flop eliminates pad-to-pad hold time. The delay is matched to the internal clock-distribution delay of the FPGA, and when used, assures that the pad-to-pad hold time is zero.

Each input buffer can be configured to conform to any of the low-voltage signalling standards supported. In some of these standards the input buffer utilizes a user-supplied threshold voltage, V_{REF}. The need to supply V_{REF} imposes constraints on which standards can be used in close proximity to each other. See **I/O Banking**.

There are optional pull-up and pull-down resistors at each user I/O input for use after configuration. Their value is in the range 50 – 100 kΩ.

Output Path

The output path includes a 3-state output buffer that drives the output signal onto the pad. The output signal can be routed to the buffer directly from the internal logic or through an optional IOB output flip-flop.

The 3-state control of the output can also be routed directly from the internal logic or through a flip-flip that provides synchronous enable and disable.

Each output driver can be individually programmed for a wide range of low-voltage signalling standards. Each output buffer can source up to 24 mA and sink up to 48 mA. Drive strength and slew rate controls minimize bus transients.

In most signalling standards, the output High voltage depends on an externally supplied V_{CCO} voltage. The need to supply V_{CCO} imposes constraints on which standards can be used in close proximity to each other. See **I/O Banking**.

An optional weak-keeper circuit is connected to each output. When selected, the circuit monitors the voltage on the pad and weakly drives the pin High or Low to match the input signal. If the pin is connected to a multiple-source signal, the weak keeper holds the signal in its last state if all drivers are disabled. Maintaining a valid logic level in this way eliminates bus chatter.

Since the weak-keeper circuit uses the IOB input buffer to monitor the input level, an appropriate V_{REF} voltage must be provided if the signalling standard requires one. The provision of this voltage must comply with the I/O banking rules.

I/O Banking

Some of the I/O standards described above require V_{CCO} and/or V_{REF} voltages. These voltages are externally supplied and connected to device pins that serve groups of IOBs, called banks. Consequently, restrictions exist about which I/O standards can be combined within a given bank.

Development System

Virtex-E FPGAs are supported by the Xilinx Foundation and Alliance Series CAE tools. The basic methodology for Virtex-E design consists of three interrelated steps: design entry, implementation, and verification. Industry-standard tools are used for design entry and simulation (for example, Synopsys FPGA Express), while Xilinx provides proprietary architecture-specific tools for implementation.

The Xilinx development system is integrated under the Xilinx Design Manager (XDM™) software, providing designers with a common user interface regardless of their choice of entry and verification tools. The XDM software simplifies the selection of implementation options with pull-down menus and on-line help.

Application programs ranging from schematic capture to Placement and Routing (PAR) can be accessed through the XDM software. The program command sequence is generated prior to execution, and stored for documentation.

Several advanced software features facilitate Virtex-E design. RPMs, for example, are schematic-based macros with relative location constraints to guide their placement. They help ensure optimal implementation of common functions.

For HDL design entry, the Xilinx FPGA Foundation development system provides interfaces to the following synthesis design environments.

- Synopsys (FPGA Compiler, FPGA Express)
- Exemplar (Spectrum)
- Synplicity (Synplify)

For schematic design entry, the Xilinx FPGA Foundation and Alliance development system provides interfaces to the following schematic-capture design environments.

- Mentor Graphics V8 (Design Architect, QuickSim II)
- Viewlogic Systems (Viewdraw)

Third-party vendors support many other environments.

A standard interface-file specification, Electronic Design Interchange Format (EDIF), simplifies file transfers into and out of the development system.

Virtex-E FPGAs are supported by a unified library of standard functions. This library contains over 400 primitives and macros, ranging from 2-input AND gates to 16-bit accumulators, and includes arithmetic functions, comparators, counters, data registers, decoders, encoders, I/O functions, latches, Boolean functions, multiplexers, shift registers, and barrel shifters.

The “soft macro” portion of the library contains detailed descriptions of common logic functions, but does not contain any partitioning or placement information. The performance of these macros depends, therefore, on the partitioning and placement obtained during implementation.

RPMs, on the other hand, do contain predetermined partitioning and placement information that permits optimal implementation of these functions. Users can create their own library of soft macros or RPMs based on the macros and primitives in the standard library.

The design environment supports hierarchical design entry, with high-level schematics that comprise major functional blocks, while lower-level schematics define the logic in these blocks. These hierarchical design elements are automatically combined by the implementation tools. Different design entry tools can be combined within a hierarchical design, thus allowing the most convenient entry method to be used for each portion of the design.

Design Implementation

The place-and-route tools (PAR) automatically provide the implementation flow described in this section. The partitioner takes the EDIF net list for the design and maps the logic into the architectural resources of the FPGA (CLBs and IOBs, for example). The placer then determines the best locations for these blocks based on their interconnections and the desired performance. Finally, the router interconnects the blocks.

The PAR algorithms support fully automatic implementation of most designs. For demanding applications, however, the user can exercise various degrees of control over the process. User partitioning, placement, and routing information is optionally specified during the design-entry process. The implementation of highly structured designs can benefit greatly from basic floor planning.

The implementation software incorporates Timing Wizard® timing-driven placement and routing. Designers specify timing requirements along entire paths during design entry. The timing path analysis routines in PAR then recognize these user-specified requirements and accommodate them.

Timing requirements are entered on a schematic in a form directly relating to the system requirements, such as the targeted clock frequency, or the maximum allowable delay between two registers. In this way, the overall performance of the system along entire signal paths is automatically tailored to user-generated specifications. Specific timing information for individual nets is unnecessary.

Design Verification

In addition to conventional software simulation, FPGA users can use in-circuit debugging techniques. Because Xilinx devices are infinitely reprogrammable, designs can be verified in real time without the need for extensive sets of software simulation vectors.

The development system supports both software simulation and in-circuit debugging techniques. For simulation, the system extracts the post-layout timing information from the design database, and back-annotates this information into the net list for use by the simulator. Alternatively, the user can verify timing-critical portions of the design using the TRCE® static timing analyzer.

IOB Flip-Flop/Latch Property

The Virtex-E series I/O Block (IOB) includes an optional register on the input path, an optional register on the output path, and an optional register on the 3-state control pin. The design implementation software automatically takes advantage of these registers when the following option for the Map program is specified.

map –pr b <filename>

Alternatively, the IOB = TRUE property can be placed on a register to force the mapper to place the register in an IOB.

Location Constraints

Specify the location of each SelectI/O symbol with the location constraint LOC attached to the SelectI/O symbol. The external port identifier indicates the value of the location constrain. The format of the port identifier depends on the package chosen for the specific design.

The LOC properties use the following form:

LOC=A42

LOC=P37

Output Slew Rate Property

As mentioned above, a variety of symbol names provide the option of choosing the desired slew rate for the output buffers. In the case of the LVTTL output buffers (OBUF, OBUFT, and IOBUF), slew rate control can be alternatively programed with the SLEW= property. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals. The SLEW= property has one of the two following values.

SLEW=SLOW

SLEW=FAST

Output Drive Strength Property

The desired output drive strength can be additionally specified by choosing the appropriate library symbol. The Xilinx library also provides an alternative method for specifying this feature. For the LVTTL output buffers (OBUF, OBUFT, and IOBUF, the desired drive strength can be specified with the DRIVE= property. This property could have one of the following seven values.

DRIVE=2
DRIVE=4
DRIVE=6
DRIVE=8
DRIVE=12 (Default)
DRIVE=16
DRIVE=24

Design Considerations

Reference Voltage (V_{REF}) Pins

Low-voltage I/O standards with a differential amplifier input buffer require an input reference voltage (V_{REF}). Provide the V_{REF} as an external signal to the device.

The voltage reference signal is “banked” within the device on a half-edge basis such that for all packages there are eight independent V_{REF} banks internally. See Figure 38 for a representation of the Virtex-E I/O banks. Within each bank approximately one of every six I/O pins is automatically configured as a V_{REF} input. After placing a differential amplifier input signal within a given V_{REF} bank, the same external source must drive all I/O pins configured as a V_{REF} input.

Within each V_{REF} bank, any input buffers that require a V_{REF} signal must be of the same type. Output buffers of any type and input buffers can be placed without requiring a reference voltage within the same V_{REF} bank.

Output Drive Source Voltage (V_{CCO}) Pins

Many of the low voltage I/O standards supported by SelectI/O devices require a different output drive source voltage (V_{CCO}). As a result each device can often have to support multiple output drive source voltages.

The Virtex-E series supports eight banks for the HQ and PQ packages. The CS package supports four V_{CCO} banks.

Output buffers within a given V_{CCO} bank must share the same output drive source voltage. Input buffers for LVTTL, LVCMOS2, LVCMOS18, PCI33_3, and PCI 66_3 use the V_{CCO} voltage for Input V_{CCO} voltage.

Transmission Line Effects

The delay of an electrical signal along a wire is dominated by the rise and fall times when the signal travels a short distance. Transmission line delays vary with inductance and capacitance, but a well-designed board can experience delays of approximately 180 ps per inch.

Transmission line effects, or reflections, typically start at 1.5" for fast (1.5 ns) rise and fall times. Poor (or non-existent) termination or changes in the transmission line impedance cause these reflections and can cause additional delay in longer traces. As system speeds continue to increase, the effect of I/O delays can become a limiting factor and therefore transmission line termination becomes increasingly more important.

Termination Techniques

A variety of termination techniques reduce the impact of transmission line effects.

The following are output termination techniques:

- None
- Series
- Parallel (Shunt)
- Series and Parallel (Series-Shunt)

Input termination techniques include the following.

- None
- Parallel (Shunt)

These termination techniques can be applied in any combination. A generic example of each combination of termination methods appears in Figure 43.

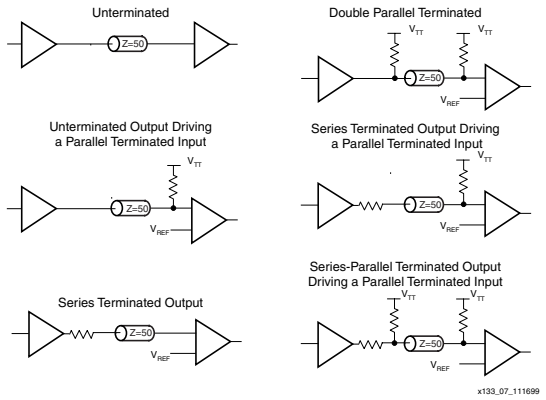

Figure 43: **Overview of Standard Input and Output Termination Methods**

Simultaneous Switching Guidelines

Ground bounce can occur with high-speed digital ICs when multiple outputs change states simultaneously, causing undesired transient behavior on an output, or in the internal logic. This problem is also referred to as the Simultaneous Switching Output (SSO) problem.

Ground bounce is primarily due to current changes in the combined inductance of ground pins, bond wires, and ground metallization. The IC internal ground level deviates from the external system ground level for a short duration (a few nanoseconds) after multiple outputs change state simultaneously.

Ground bounce affects stable Low outputs and all inputs because they interpret the incoming signal by comparing it to the internal ground. If the ground bounce amplitude exceeds the actual instantaneous noise margin, then a non-changing input can be interpreted as a short pulse with a polarity opposite to the ground bounce.

Table 21 provides guidelines for the maximum number of simultaneously switching outputs allowed per output power/ground pair to avoid the effects of ground bounce. See Table 22 for the number of effective output power/ground pairs for each Virtex-E device and package combination.

Table 21: **Guidelines for Max Number of Simultaneously Switching Outputs per Power/Ground Pair**

Standard	Package		
	BGA, CS, FGA	HQ	PQ, TQ
LVTTL Slow Slew Rate, 2 mA drive	68	49	36
LVTTL Slow Slew Rate, 4 mA drive	41	31	20
LVTTL Slow Slew Rate, 6 mA drive	29	22	15
LVTTL Slow Slew Rate, 8 mA drive	22	17	12
LVTTL Slow Slew Rate, 12 mA drive	17	12	9
LVTTL Slow Slew Rate, 16 mA drive	14	10	7
LVTTL Slow Slew Rate, 24 mA drive	9	7	5
LVTTL Fast Slew Rate, 2 mA drive	40	29	21
LVTTL Fast Slew Rate, 4 mA drive	24	18	12
LVTTL Fast Slew Rate, 6 mA drive	17	13	9
LVTTL Fast Slew Rate, 8 mA drive	13	10	7
LVTTL Fast Slew Rate, 12 mA drive	10	7	5
LVTTL Fast Slew Rate, 16 mA drive	8	6	4
LVTTL Fast Slew Rate, 24 mA drive	5	4	3
LVCMOS	10	7	5
PCI	8	6	4
GTL	4	4	4
GTL+	4	4	4

Date	Version	Revision
9/20/00	1.7	• Min values added to **Virtex-E Electrical Characteristics** tables. • XCV2600E and XCV3200E numbers added to **Virtex-E Electrical Characteristics** tables (Module 3). • Corrected user I/O count for XCV100E device in Table 1 (Module 1). • Changed several pins to “No Connect in the XCV100E“ and removed duplicate V_{CCINT} pins in Table ~ (Module 4). • Changed pin J10 to “No connect in XCV600E” in Table 74 (Module 4). • Changed pin J30 to “VREF option only in the XCV600E” in Table 74 (Module 4). • Corrected pair 18 in Table 75 (Module 4) to be “AO in the XCV1000E, XCV1600E“.
11/20/00	1.8	• Upgraded speed grade -8 numbers in **Virtex-E Electrical Characteristics** tables to Preliminary. • Updated minimums in Table 13 and added notes to Table 14. • Added to note 2 to **Absolute Maximum Ratings**. • Changed speed grade -8 numbers for $T_{SHCKO32}$, T_{REG}, T_{BCCS}, and T_{ICKOF}. • Changed all minimum hold times to –0.4 under **Global Clock Set-Up and Hold for LVTTL Standard, with DLL**. • Revised maximum T_{DLLPW} in -6 speed grade for **DLL Timing Parameters**. • Changed GCLK0 to BA22 for FG860 package in Table 46.
2/12/01	1.9	• Revised footnote for Table 14. • Added numbers to **Virtex-E Electrical Characteristics** tables for XCV1000E and XCV2000E devices. • Updated Table 27 and Table 78 to include values for XCV400E and XCV600E devices. • Revised Table 62 to include pinout information for the XCV400E and XCV600E devices in the BG560 package. • Updated footnotes 1 and 2 for Table 76 to include XCV2600E and XCV3200E devices.
4/02/01	2.0	• Updated numerous values in **Virtex-E Switching Characteristics** tables. • Converted data sheet to modularized format. See the **Virtex-E Data Sheet** section.
4/19/01	2.1	• Modified Figure 30 "DLL Generation of 4x Clock in Virtex-E Devices."
07/23/01	2.2	• Made minor edits to text under **Configuration**. • Added CLB column locations for XCV2600E anbd XCV3200E devices in Table 3.
11/09/01	2.3	• Added warning under **Configuration** section that attempting to load an incorrect bitstream causes configuration to fail and can damage the device.
07/17/02	2.4	• Data sheet designation upgraded from Preliminary to Production.
09/10/02	2.5	• Added clarification to the **Input/Output Block**, **Configuration**, **Boundary Scan Mode**, and **Block SelectRAM** sections. Revised Figure 18, Table 11, and Table 36.
11/19/02	2.6	• Added clarification in the **Boundary Scan** section. • Removed last sentence regarding deactivation of duty-cycle correction in **Duty Cycle Correction Property** section.
06/15/04	2.6.1	• Updated clickable web addresses.
01/12/06	2.7	• Updated the **Slave-Serial Mode** and the **Master-Serial Mode** sections.
01/16/06	2.8	• Made minor updates to Table 8.

Virtex-E Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation net list. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Virtex-E devices unless otherwise noted.

IOB Input Switching Characteristics

Input delays associated with the pad are specified for LVTTL levels in Table 2. For other standards, adjust the delays with the values shown in **IOB Input Switching Characteristics Standard Adjustments**, page 8.

Table 2: **IOB Input Switching Characteristics**

			Speed Grade(1)				
Description(2)	**Symbol**	**Device**	**Min**	**-8**	**-7**	**-6**	**Units**
Propagation Delays							
Pad to I output, no delay	T_{IOPI}	All	0.43	0.8	0.8	0.8	ns, max
Pad to I output, with delay	T_{IOPID}	XCV50E	0.51	1.0	1.0	1.0	ns, max
		XCV100E	0.51	1.0	1.0	1.0	ns, max
		XCV200E	0.51	1.0	1.0	1.0	ns, max
		XCV300E	0.51	1.0	1.0	1.0	ns, max
		XCV400E	0.51	1.0	1.0	1.0	ns, max
		XCV600E	0.51	1.0	1.0	1.0	ns, max
		XCV1000E	0.55	1.1	1.1	1.1	ns, max
		XCV1600E	0.55	1.1	1.1	1.1	ns, max
		XCV2000E	0.55	1.1	1.1	1.1	ns, max
		XCV2600E	0.55	1.1	1.1	1.1	ns, max
		XCV3200E	0.55	1.1	1.1	1.1	ns, max
Pad to output IQ via transparent latch, no delay	T_{IOPLI}	All	0.8	1.4	1.5	1.6	ns, max
Pad to output IQ via transparent latch, with delay	T_{IOPLID}	XCV50E	1.31	2.9	3.0	3.1	ns, max
		XCV100E	1.31	2.9	3.0	3.1	ns, max
		XCV200E	1.39	3.1	3.2	3.3	ns, max
		XCV300E	1.39	3.1	3.2	3.3	ns, max
		XCV400E	1.43	3.2	3.3	3.4	ns, max
		XCV600E	1.55	3.5	3.6	3.7	ns, max
		XCV1000E	1.55	3.5	3.6	3.7	ns, max
		XCV1600E	1.59	3.6	3.7	3.8	ns, max
		XCV2000E	1.59	3.6	3.7	3.8	ns, max
		XCV2600E	1.59	3.6	3.7	3.8	ns, max
		XCV3200E	1.59	3.6	3.7	3.8	ns, max

Table 2: **IOB Input Switching Characteristics *(Continued)***

Description[2]	Symbol	Device	Speed Grade[1] Min	-8	-7	-6	Units
Sequential Delays							
Clock CLK							
Minimum Pulse Width, High	T_{CH}	All	0.56	1.2	1.3	1.4	ns, min
Minimum Pulse Width, Low	T_{CL}		0.56	1.2	1.3	1.4	ns, min
Clock CLK to output IQ	T_{IOCKIQ}		0.18	0.4	0.7	0.7	ns, max
Setup and Hold Times with respect to Clock at IOB Input Register							
Pad, no delay	T_{IOPICK}/ T_{IOICKP}	All	0.69 / 0	1.3 / 0	1.4 / 0	1.5 / 0	ns, min
Pad, with delay	$T_{IOPICKD}$/ $T_{IOICKPD}$	XCV50E	1.25 / 0	2.8 / 0	2.9 / 0	2.9 / 0	ns, min
		XCV100E	1.25 / 0	2.8 / 0	2.9 / 0	2.9 / 0	ns, min
		XCV200E	1.33 / 0	3.0 / 0	3.1 / 0	3.1 / 0	ns, min
		XCV300E	1.33 / 0	3.0 / 0	3.1 / 0	3.1 / 0	ns, min
		XCV400E	1.37 / 0	3.1 / 0	3.2 / 0	3.2 / 0	ns, min
		XCV600E	1.49 / 0	3.4 / 0	3.5 / 0	3.5 / 0	ns, min
		XCV1000E	1.49 / 0	3.4 / 0	3.5 / 0	3.5 / 0	ns, min
		XCV1600E	1.53 / 0	3.5 / 0	3.6 / 0	3.6 / 0	ns, min
		XCV2000E	1.53 / 0	3.5 / 0	3.6 / 0	3.6 / 0	ns, min
		XCV2600E	1.53 / 0	3.5 / 0	3.6 / 0	3.6 / 0	ns, min
		XCV3200E	1.53 / 0	3.5 / 0	3.6 / 0	3.6 / 0	ns, min
ICE input	$T_{IOICECK}$/ $T_{IOCKICE}$	All	0.28 / 0.0	0.55 / 0.01	0.7 / 0.01	0.7 / 0.01	ns, min
SR input (IFF, synchronous)	$T_{IOSRCKI}$	All	0.38	0.8	0.9	1.0	ns, min
Set/Reset Delays							
SR input to IQ (asynchronous)	T_{IOSRIQ}	All	0.54	1.1	1.2	1.4	ns, max
GSR to output IQ	T_{GSRQ}	All	3.88	7.6	8.5	9.7	ns, max

Notes:
1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.
2. Input timing i for LVTTL is measured at 1.4 V. For other I/O standards, see Table 4.

Global Clock Input to Output Delay for LVTTL, 12 mA, Fast Slew Rate, *without* DLL

Description[1]	Symbol	Device	Speed Grade[2]				Units
			Min	-8	-7	-6	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, *without* DLL. For data *output* with different standards, adjust the delays with the values shown in **IOB Output Switching Characteristics Standard Adjustments**, page 10.	T_{ICKOF}	XCV50E	1.5	4.2	4.4	4.6	ns
		XCV100E	1.5	4.2	4.4	4.6	ns
		XCV200E	1.5	4.3	4.5	4.7	ns
		XCV300E	1.5	4.3	4.5	4.7	ns
		XCV400E	1.5	4.4	4.6	4.8	ns
		XCV600E	1.6	4.5	4.7	4.9	ns
		XCV1000E	1.7	4.6	4.8	5.0	ns
		XCV1600E	1.8	4.7	4.9	5.1	ns
		XCV2000E	1.8	4.8	5.0	5.2	ns
		XCV2600E	2.0	5.0	5.2	5.4	ns
		XCV3200E	2.2	5.2	5.4	5.6	ns

Notes:
1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 50% V_{CC} threshold with 35 pF external capacitive load. For other I/O standards and different loads, see Table 3 and Table 4.

Table 10: **BG352 — XCV100E, XCV200E, XCV300E**

Bank	Pin Description	Pin #
0	IO	C15
0	IO	B15[1]
0	IO_LVDS_DLL_L9N	A15
0	GCK3	D14
1	GCK2	B14
1	IO_LVDS_DLL_L9P	A13
1	IO	B13[1]
1	IO_L10N	C13
1	IO_L10P	A12
1	IO_L11N_Y	B12
1	IO_VREF_1_L11P_Y	C12
1	IO_L12N_Y	A11
1	IO_L12P_Y	B11
1	IO	B10[1]
1	IO_L13N	C11
1	IO_L13P	D11
1	IO	A9[1]
1	IO_L14N_YY	B9
1	IO_L14P_YY	C10
1	IO_L15N_YY	B8
1	IO_VREF_1_L15P_YY	C9
1	IO_L16N _Y	D9
1	IO_L16P _Y	A7
1	IO	B7
1	IO	C8[1]
1	IO	D8[1]
1	IO_L17N_YY	A6
1	IO_VREF_1_L17P_YY	B6
1	IO_L18N_YY	C7
1	IO_L18P_YY	A4
1	IO	B5[1]
1	IO_L19N_YY	C6
1	IO_VREF_1_L19P_YY	D6[2]

Table 10: **BG352 — XCV100E, XCV200E, XCV300E**

Bank	Pin Description	Pin #
1	IO	B4
1	IO	C5[1]
1	IO	A3[1]
1	IO_WRITE_L20N_YY	D5
1	IO_CS_L20P_YY	C4
2	IO_DOUT_BUSY_L21P_YY	E4
2	IO_DIN_D0_L21N_YY	D3
2	IO	C2[1]
2	IO	E3[1]
2	IO	F4
2	IO_VREF_2_L22P_YY	D2[2]
2	IO_L22N_YY	C1
2	IO	D1[1]
2	IO_L23P_YY	G4
2	IO_L23N_YY	F3
2	IO_VREF_2_L24P_Y	E2
2	IO_L24N_Y	F2
2	IO	G3[1]
2	IO	G2[1]
2	IO_L25P	F1
2	IO_L25N	J4
2	IO	H3
2	IO_VREF_2_L26P _Y	H2
2	IO_D1_L26N _Y	G1
2	IO_D2_L27P_YY	J3
2	IO_L27N_YY	J2
2	IO	K3[1]
2	IO_L28P	J1
2	IO_L28N	L4
2	IO	K2[1]
2	IO_L29P_YY	L3
2	IO_L29N_YY	L2
2	IO_VREF_2_L30P _Y	M4

Table 10: **BG352 — XCV100E, XCV200E, XCV300E**

Bank	Pin Description	Pin #
6	IO_L74P _Y	R25
6	IO_L75N	R26
6	IO_L75P	P24
6	IO	P23[1]
6	IO	N26
7	IO_L76N_YY	N25
7	IO_L76P_YY	N24
7	IO	M26[1]
7	IO_L77N	M25
7	IO_L77P	M24
7	IO_L78N _Y	M23
7	IO_VREF_7_L78P _Y	L26
7	IO_L79N_YY	K25
7	IO_L79P_YY	L24
7	IO	L23[1]
7	IO_L80N	J26
7	IO_L80P	J25
7	IO	K24[1]
7	IO_L81N_YY	K23
7	IO_L81P_YY	H25
7	IO_L82N _Y	J23
7	IO_VREF_7_L82P _Y	G26
7	IO_L83N _Y	G25
7	IO_L83P _Y	H24
7	IO	H23
7	IO	F26[1]
7	IO	F25[1]
7	IO_L84N_Y	G24
7	IO_VREF_7_L84P_Y	D26
7	IO_L85N_YY	E25
7	IO_L85P_YY	F24
7	IO	F23[1]
7	IO_L86N_YY	D25

Table 10: **BG352 — XCV100E, XCV200E, XCV300E**

Bank	Pin Description	Pin #
7	IO_VREF_7_L86P_YY	E24[2]
7	IO	C26
7	IO	E23[1]
7	IO	D24[1]
7	IO	C25
NA	TDI	B3
NA	TDO	D4
NA	CCLK	C3
NA	TCK	C24
NA	TMS	D23
NA	PROGRAM	AC4
NA	DONE	AD3
NA	DXN	AD23
NA	DXP	AE24
NA	M2	AC23
NA	M0	AD24
NA	M1	AB23
NA	VCCINT	A20
NA	VCCINT	B16
NA	VCCINT	C14
NA	VCCINT	D12
NA	VCCINT	D10
NA	VCCINT	K4
NA	VCCINT	L1
NA	VCCINT	P2
NA	VCCINT	T1
NA	VCCINT	W2
NA	VCCINT	AC10
NA	VCCINT	AF11
NA	VCCINT	AE14
NA	VCCINT	AF16
NA	VCCINT	AE19

BG352 Differential Pin Pairs

Virtex-E devices have differential pin pairs that can also provide other functions when not used as a differential pair. A check (√) in the AO column indicates that the pin pair can be used as an asynchronous output for all devices provided in this package. Pairs with a note number in the AO column are device dependent. They can have asynchronous outputs if the pin pair are in the same CLB row and column in the device. Numbers in this column refer to footnotes that indicate which devices have pin pairs than can be asynchronous outputs. The Other Functions column indicates alternative function(s) not available when the pair is used as a differential pair or differential clock

Table 11: **BG352 Differential Pin Pair Summary XCV100E, XCV200E, XCV300E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
Global Differential Clock					
0	4	AE13	AC13	NA	IO LVDS 55
1	5	AF14	AD14	NA	IO LVDS 55
2	1	B14	A13	NA	IO LVDS 9
3	0	D14	A15	NA	IO LVDS 9
IO LVDS Total Outputs: 87, Asynchronous Output Pairs: 43					
0	0	B23	D21	√	VREF_0
1	0	D20	A23	√	-
2	0	B22	C21	√	VREF_0
3	0	A21	B20	2	-
4	0	B19	C19	√	VREF_0
5	0	C18	D17	√	-
6	0	A18	C17	2	-
7	0	C16	B17	√	-
8	0	D15	A16	√	VREF_0
9	1	A13	A15	√	GCLK LVDS 3/2
10	1	A12	C13	2	-
11	1	C12	B12	√	VREF_1
12	1	B11	A11	√	-
13	1	D11	C11	2	-
14	1	C10	B9	√	-
15	1	C9	B8	√	VREF_1
16	1	A7	D9	1	-
17	1	B6	A6	√	VREF_1
18	1	A4	C7	√	-

Table 11: **BG352 Differential Pin Pair Summary XCV100E, XCV200E, XCV300E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
19	1	D6	C6	√	VREF_1
20	1	C4	D5	√	CS
21	2	E4	D3	√	DIN_D0
22	2	D2	C1	√	VREF_2
23	2	G4	F3	√	-
24	2	E2	F2	√	VREF_2
25	2	F1	J4	2	-
26	2	H2	G1	√	D1
27	2	J3	J2	√	D2
28	2	J1	L4	1	-
29	2	L3	L2	√	-
30	2	M4	M3	√	D3
31	2	M2	M1	2	-
32	2	N4	N2	√	-
33	3	R1	R2	2	-
34	3	R3	R4	√	VREF_3
35	3	T2	U2	√	-
36	3	T4	V1	1	-
37	3	U3	U4	√	D5
38	3	V3	V4	√	VREF_3
39	3	Y1	Y2	1	-
40	3	AA2	Y3	√	VREF_3
41	3	AC1	AB2	√	-
42	3	AA4	AC2	√	VREF_3
43	3	AC3	AD2	√	INIT
44	4	AC5	AD4	√	-
45	4	AE4	AF3	√	VREF_4
46	4	AC7	AD6	√	-
47	4	AE5	AE6	√	VREF_4
48	4	AF6	AC9	2	-
49	4	AE8	AF7	√	VREF_4
50	4	AD9	AE9	√	-
51	4	AF9	AC11	2	-
52	4	AD11	AE11	√	-
53	4	AC12	AD12	√	VREF_4
54	4	AE12	AF12	2	-

Table 13: **BG432 Differential Pin Pair Summary XCV300E, XCV400E, XC600E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
48	2	N1	P4	√	D3
49	2	P3	P2	4	-
50	2	R3	R4	1	VREF
51	2	R1	T3	√	-
52	3	U4	U2	1	VREF
53	3	U1	V3	4	-
54	3	V4	V2	√	VREF
55	3	W3	W4	1	-
56	3	Y1	Y3	1	-
57	3	Y4	Y2	4	-
58	3	AA3	AB1	√	D5
59	3	AB3	AB4	√	VREF
60	3	AD1	AC3	1	VREF
61	3	AC4	AD2	4	-
62	3	AD3	AD4	√	VREF
63	3	AF2	AE3	1	-
64	3	AE4	AG1	5	-
65	3	AG2	AF3	1	VREF
66	3	AF4	AH1	4	-
67	3	AH2	AG3	3	-
68	3	AG4	AJ2	√	INIT
69	4	AJ4	AK3	√	-
70	4	AH5	AK4	1	-
71	4	AJ5	AH6	√	-
72	4	AL4	AK5	√	VREF
73	4	AJ6	AH7	2	-
74	4	AL5	AK6	√	-
75	4	AJ7	AL6	√	VREF
76	4	AH9	AJ8	1	-
77	4	AK8	AJ9	1	VREF
78	4	AL8	AK9	√	VREF
79	4	AK10	AL10	√	-

Table 13: **BG432 Differential Pin Pair Summary XCV300E, XCV400E, XC600E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
80	4	AH12	AK11	√	-
81	4	AJ12	AK12	√	-
82	4	AH13	AJ13	√	-
83	4	AL13	AK14	√	VREF
84	4	AH14	AJ14	1	-
85	4	AK15	AJ15	1	VREF
86	5	AH15	AL17	NA	IO_LVDS_DLL
87	5	AK17	AJ17	1	VREF
88	5	AH17	AK18	1	-
89	5	AL19	AJ18	√	VREF
90	5	AH18	AL20	√	-
91	5	AK20	AH19	√	-
92	5	AJ20	AK21	√	-
93	5	AJ21	AL22	√	-
94	5	AJ22	AK23	√	VREF
95	5	AH22	AL24	1	VREF
96	5	AK24	AH23	1	-
97	5	AK25	AJ25	√	VREF
98	5	AL26	AK26	√	-
99	5	AH25	AL27	2	-
100	5	AJ26	AK27	√	VREF
101	5	AH26	AL28	√	-
102	5	AJ27	AK28	1	-
103	6	AH30	AJ30	√	-
104	6	AH31	AG28	3	-
105	6	AG30	AG29	4	-
106	6	AG31	AF28	1	VREF
107	6	AF30	AF29	5	-
108	6	AF31	AE28	1	-
109	6	AD28	AE30	√	VREF
110	6	AD31	AD30	4	-
111	6	AC29	AC28	1	VREF

Table 16: **FG256 Package — XCV50E, XCV100E, XCV200E, XCV300E**

Bank	Pin Description	Pin #
4	IO_L43P_Y	P12
4	IO_VREF_L43N_Y	R13[2]
4	IO_L44P_YY	N12
4	IO_L44N_YY	T13
4	IO_VREF_L45P_YY	T12
4	IO_L45N_YY	P11
4	IO_L46P_Y	R12
4	IO_L46N_Y	N11
4	IO_VREF_L47P_YY	T11[1]
4	IO_L47N_YY	M11
4	IO_L48P_YY	R11
4	IO_L48N_YY	T10
4	IO_L49P_Y	R10
4	IO_L49N_Y	M10
4	IO_VREF_L50P_Y	P9
4	IO_L50N_Y	T9
4	IO_L51P_Y	N10
4	IO_L51N_Y	R9
4	IO_LVDS_DLL_L52P	N9
5	GCK1	R8
5	IO	N7
5	IO	T7
5	IO_LVDS_DLL_L52N	T8
5	IO_L53P_Y	R7
5	IO_VREF_L53N_Y	P8
5	IO_L54P_Y	P7
5	IO_L54N_Y	T6
5	IO_L55P_YY	M7
5	IO_L55N_YY	R6
5	IO_L56P_YY	P6
5	IO_VREF_L56N_YY	R5[1]
5	IO_L57P_Y	N6
5	IO_L57N_Y	T5
5	IO_L58P_YY	M6

Table 16: **FG256 Package — XCV50E, XCV100E, XCV200E, XCV300E**

Bank	Pin Description	Pin #
5	IO_VREF_L58N_YY	T4
5	IO_L59P_YY	T3
5	IO_L59N_YY	P5
5	IO_VREF_L60P_Y	T2[2]
5	IO_L60N_Y	N5
6	IO_L61N_YY	M3
6	IO_L61P_YY	R1
6	IO_L62N	M4
6	IO_VREF_L62P	N2[2]
6	IO_L63N_YY	L5
6	IO_L63P_YY	P1
6	IO_VREF_L64N_Y	N1
6	IO_L64P_Y	L3
6	IO_L65N	M2
6	IO_L65P	L4
6	IO_VREF_L66N_Y	M1[1]
6	IO_L66P_Y	K4
6	IO_L67N_YY	L2
6	IO_L67P_YY	L1
6	IO_L68N	K3
6	IO_L68P	K1
6	IO_L69N_YY	K2
6	IO_L69P_YY	K5
6	IO_VREF_L70N_Y	J3
6	IO_L70P_Y	J1
6	IO_L71N	J4
6	IO_L71P	H1
6	IO	J2
7	IO	C2
7	IO_L72N_YY	G1
7	IO_L72P_YY	H4
7	IO_L73N	G5
7	IO_L73P	H2

Table 16: **FG256 Package — XCV50E, XCV100E, XCV200E, XCV300E**

Bank	Pin Description	Pin #
NA	GND	K11
NA	GND	K10
NA	GND	K9
NA	GND	K8
NA	GND	K7
NA	GND	K6
NA	GND	J10
NA	GND	J9
NA	GND	J8
NA	GND	J7
NA	GND	H10
NA	GND	H9
NA	GND	H8
NA	GND	H7
NA	GND	G11
NA	GND	G10
NA	GND	G9
NA	GND	G8
NA	GND	G7
NA	GND	G6
NA	GND	F11
NA	GND	F10
NA	GND	F7
NA	GND	F6
NA	GND	B15
NA	GND	B2
NA	GND	A16
NA	GND	A1

Notes:
1. V_{REF} or I/O option only in the XCV100E, 200E, 300E; otherwise, I/O option only.
2. V_{REF} or I/O option only in the XCV200E, 300E; otherwise, I/O option only.

FG256 Differential Pin Pairs

Virtex-E devices have differential pin pairs that can also provide other functions when not used as a differential pair. A √ in the AO column indicates that the pin pair can be used as an asynchronous output for all devices provided in this package. Pairs with a note number in the AO column are device dependent. They can have asynchronous outputs if the pin pair are in the same CLB row and column in the device. Numbers in this column refer to footnotes that indicate which devices have pin pairs than can be asynchronous outputs. The Other Functions column indicates alternative function(s) not available when the pair is used as a differential pair or differential clock.

Table 17: **FG256 Differential Pin Pair Summary XCV50E, XCV100E, XCV200E, XCV300E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
Global Differential Clock					
0	4	N8	N9	NA	IO_DLL_L52P
1	5	R8	T8	NA	IO_DLL_L52N
2	1	C9	A8	NA	IO_DLL_L8P
3	0	B8	A7	NA	IO_DLL_L8N
IO LVDS Total Pairs: 83, Asynchronous Outputs: 35					
0	0	A3	C5	7	VREF
1	0	E6	D5	√	-
2	0	A4	B4	√	VREF
3	0	B5	D6	2	-
4	0	A5	C6	√	VREF
5	0	C7	B6	√	-
6	0	C8	D7	1	-
7	0	A6	B7	1	VREF
8	1	A8	A7	NA	IO_LVDS_DLL
9	1	A9	D9	2	-
10	1	B9	E10	1	VREF
11	1	D10	A10	1	-
12	1	A11	C10	√	-
13	1	E11	B11	√	VREF
14	1	D11	A12	2	-
15	1	C11	A13	√	VREF
16	1	D12	B12	√	-
17	1	C12	A14	7	VREF
18	1	B13	C13	√	CS

Table 19: **FG456 Differential Pin Pair Summary XCV200E, XCV300E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
18	1	C14	B14	2	-
19	1	A15	F12	2	-
20	1	C15	B15	√	-
21	1	E14	A16	√	VREF
22	1	C16	D14	2	-
23	1	A17	D15	2	-
24	1	A18	B17	√	VREF
25	1	C17	D16	√	-
26	1	A19	B18	√	VREF
27	1	C18	D17	√	-
28	1	C19	A20	√	CS
29	2	C21	D20	√	DIN, D0
30	2	C22	D21	√	-
31	2	D22	E21	√	VREF
32	2	E22	F18	√	-
33	2	F21	F19	√	VREF
34	2	F22	G19	2	-
35	2	G20	G18	1	-
36	2	H18	H22	2	D1, VREF
37	2	H20	H19	√	D2
38	2	H21	J19	√	-
39	2	J18	J20	√	-
40	2	K18	J21	2	-
41	2	K22	K21	1	VREF
42	2	K19	L22	2	-
43	2	L21	L18	√	-
44	2	L17	L20	√	-
45	3	M18	M20	√	-
46	3	M19	M17	2	-
47	3	N22	N21	2	VREF
48	3	N20	N18	√	-
49	3	N19	P21	√	-
50	3	P20	P19	√	-
51	3	P18	R21	√	D5
52	3	T22	R19	2	VREF

Table 19: **FG456 Differential Pin Pair Summary XCV200E, XCV300E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
53	3	U22	R18	2	-
54	3	T21	V22	√	-
55	3	T20	U21	√	VREF
56	3	W22	T18	√	-
57	3	U19	U20	√	VREF
58	3	W21	AA22	√	-
59	3	Y21	V19	√	INIT
60	4	W18	AA20	√	-
61	4	Y18	V17	NA	-
62	4	AB20	W17	√	VREF
63	4	AA18	V16	NA	-
64	4	AB19	AB18	√	VREF
65	4	W16	AA17	1	-
66	4	Y16	V15	1	-
67	4	AB16	Y15	√	VREF
68	4	AA15	AB15	√	-
69	4	W15	Y14	1	-
70	4	V14	AA14	1	-
71	4	AB14	V13	NA	-
72	4	AA13	AB13	√	VREF
73	4	W13	AA12	2	-
74	4	Y12	V12	2	-
75	5	U12	AA11	NA	IO_LVDS_DLL
76	5	AB11	W11	1	-
77	5	V11	Y10	√	VREF
78	5	AB10	W10	√	-
79	5	V10	Y9	2	-
80	5	AB9	W9	2	-
81	5	V9	AA8	√	-
82	5	Y8	W8	√	VREF
83	5	W7	AA7	2	-
84	5	AB6	AA6	2	-
85	5	AB5	AA5	√	VREF
86	5	Y7	W6	√	-
87	5	AA4	Y6	√	VREF

FG860 Fine-Pitch Ball Grid Array Package

XCV1000E, XCV1600E, and XCV2000E devices in the FG680 fine-pitch Ball Grid Array package have footprint compatibility. Pins labeled I0_VREF can be used as either in all parts unless device-dependent as indicated in the footnotes. If the pin is not used as V_{REF}, it can be used as general I/O. Immediately following Table 24, see Table 25 for Differential Pair information.

Table 24: **FG860 — XCV1000E, XCV1600E, XCV2000E**

Bank	Pin Description	Pin #
0	GCK3	C22
0	IO	A26
0	IO	B31
0	IO	B34
0	IO	C24
0	IO	C29
0	IO	C34
0	IO	D24
0	IO	D36
0	IO	D40
0	IO	E26
0	IO	E28
0	IO	E35
0	IO_L0N_Y	A38
0	IO_L0P_Y	D38
0	IO_L1N_Y	B37
0	IO_L1P_Y	E37
0	IO_VREF_L2N_Y	A37
0	IO_L2P_Y	C39
0	IO_L3N_Y	B36
0	IO_L3P_Y	C38
0	IO_L4N_YY	A36
0	IO_L4P_YY	B35
0	IO_VREF_L5N_YY	A35
0	IO_L5P_YY	D37
0	IO_L6N_Y	C37
0	IO_L6P_Y	A34
0	IO_L7N_Y	E36
0	IO_L7P_Y	B33
0	IO_L8N_YY	A33
0	IO_L8P_YY	C32
0	IO_VREF_L9N_YY	C36
0	IO_L9P_YY	B32
0	IO_L10N_Y	A32
0	IO_L10P_Y	D35
0	IO_VREF_L11N_Y	C31[2]
0	IO_L11P_Y	C35
0	IO_L12N_YY	E34
0	IO_L12P_YY	A31
0	IO_VREF_L13N_YY	D34
0	IO_L13P_YY	C30
0	IO_L14N_Y	B30
0	IO_L14P_Y	E33
0	IO_L15N_Y	A30
0	IO_L15P_Y	D33
0	IO_VREF_L16N_YY	C33
0	IO_L16P_YY	B29
0	IO_L17N_YY	E32
0	IO_L17P_YY	A29
0	IO_L18N_Y	D32
0	IO_L18P_Y	C28
0	IO_L19N_Y	E31
0	IO_L19P_Y	B28
0	IO_L20N_Y	D31
0	IO_L20P_Y	A28
0	IO_L21N_Y	D30
0	IO_L21P_Y	C27
0	IO_L22N_YY	E29
0	IO_L22P_YY	B27
0	IO_VREF_L23N_YY	D29
0	IO_L23P_YY	A27
0	IO_L24N_Y	C26
0	IO_L24P_Y	D28
0	IO_L25N_Y	B26
0	IO_L25P_Y	F27
0	IO_L26N_YY	E27
0	IO_L26P_YY	C25

Table 27: **FG900 Differential Pin Pair Summary XCV600E, XCV1000E, XCV1600E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
256	7	N6	M6	1	-
257	7	N1	N5	4	-
258	7	M5	M4	√	-
259	7	M1	M2	1	VREF
260	7	L2	L4	4	-
261	7	L5	M7	3	-
262	7	M8	L1	4	-
263	7	M9	K2	1	-
264	7	M10	L3	NA	-
265	7	K1	K5	√	-
266	7	K3	L6	√	VREF
267	7	K4	L7	4	-
268	7	J5	L8	4	-
269	7	H4	K6	4	VREF
270	7	K7	H1	4	-
271	7	J2	J7	2	-
272	7	G2	H5	√	-
273	7	G5	L9	√	VREF
274	7	K8	F3	1	-
275	7	E1	G3	4	-
276	7	E2	H6	√	-
277	7	K9	E4	1	VREF
278	7	F4	J8	4	-
279	7	H7	D1	3	-
280	7	C2	G6	4	VREF
281	7	F5	D2	1	-
282	7	K10	D3	4	-

Notes:
1. AO in the XCV600E, 1000E.
2. AO in the XCV1000E.
3. AO in the XCV1600E.
4. AO in the XCV1000E, XCV1600E.

FG1156 Fine-Pitch Ball Grid Array Package

XCV1000E, XCV1600E, XCV2000E, XCV2600E, and XCV3200E devices in the FG1156 fine-pitch Ball Grid Array package have footprint compatibility. Pins labeled IO_VREF can be used as either V_{REF} or general I/O, unless indicated in the footnotes. If the pin is not used as V_{REF}, it can be used as general I/O. Immediately following Table 28, see Table 29 for Differential Pair information.

Table 28: **FG1156 — XCV1000E, XCV1600E, XCV2000E, XCV2600E, XCV3200E**

Bank	Pin Description	Pin #
0	GCK3	E17
0	IO	B4
0	IO	B9
0	IO	B10
0	IO	D9[3]
0	IO	D16
0	IO	E7[3]
0	IO	E11[3]
0	IO	E13[3]
0	IO	E16[3]
0	IO	F17[3]
0	IO	J12[3]
0	IO	J13[3]
0	IO	J14[3]
0	IO	K11[3]
0	IO_L0N_Y	F7
0	IO_L0P_Y	H9
0	IO_L1N_Y	C5
0	IO_L1P_Y	J10
0	IO_VREF_L2N_Y	E6
0	IO_L2P_Y	D6
0	IO_L3N_Y	A4
0	IO_L3P_Y	G8
0	IO_L4N_YY	C6
0	IO_L4P_YY	J11
0	IO_VREF_L5N_YY	G9
0	IO_L5P_YY	F8
0	IO_L6N_YY	A5[4]

Table 28: **FG1156 — XCV1000E, XCV1600E, XCV2000E, XCV2600E, XCV3200E**

Bank	Pin Description	Pin #
1	IO_L66P_Y	E24
1	IO_L67N_YY	A26
1	IO_VREF_L67P_YY	C25
1	IO_L68N_YY	F24
1	IO_L68P_YY	B26
1	IO_L69N	K23[5]
1	IO_L69P	F25[4]
1	IO_L70N_Y	C26
1	IO_VREF_L70P_Y	H24[2]
1	IO_L71N_Y	G24
1	IO_L71P_Y	A27
1	IO_L72N	B27[5]
1	IO_L72P	G25[4]
1	IO_L73N_YY	E26
1	IO_VREF_L73P_YY	C27
1	IO_L74N_YY	J24
1	IO_L74P_YY	B28
1	IO_L75N	K24[5]
1	IO_L75P	H25[4]
1	IO_L76N_Y	D27
1	IO_L76P_Y	F26
1	IO_L77N_Y	G26
1	IO_L77P_Y	C28
1	IO_L78N_YY	E27[5]
1	IO_L78P_YY	J25[4]
1	IO_L79N_YY	A30
1	IO_VREF_L79P_YY	H26
1	IO_L80N_YY	G27
1	IO_L80P_YY	B29
1	IO_L81N_Y	F27
1	IO_L81P_Y	C29
1	IO_L82N_Y	E28
1	IO_VREF_L82P_Y	F28
1	IO_L83N_Y	L25

Table 28: **FG1156 — XCV1000E, XCV1600E, XCV2000E, XCV2600E, XCV3200E**

Bank	Pin Description	Pin #
1	IO_L83P_Y	B30
1	IO_L84N	B31
1	IO_L84P	E29
1	IO_WRITE_L85N_YY	A31
1	IO_CS_L85P_YY	D30
2	IO	F31[3]
2	IO	J32
2	IO	K27[3]
2	IO	K31[3]
2	IO	L28[3]
2	IO	L30[3]
2	IO	M32[3]
2	IO	N26
2	IO	N28[3]
2	IO	P25[3]
2	IO	U26[3]
2	IO	U30
2	IO	U32[3]
2	IO	U34
2	IO_D2	M30
2	IO_DOUT_BUSY_L86P_YY	D32
2	IO_DIN_D0_L86N_YY	J27
2	IO_L87P_Y	E31
2	IO_L87N_Y	F30
2	IO_L88P_Y	G29
2	IO_L88N_Y	F32
2	IO_VREF_L89P_Y	E32
2	IO_L89N_Y	G30
2	IO_L90P	M25
2	IO_L90N	G31
2	IO_L91P_Y	L26
2	IO_L91N_Y	D33
2	IO_VREF_L92P_Y	D34

Table 29: **FG1156 Differential Pin Pair Summary: XCV1000E, XCV1600E, XCV2000E, XCV2600E, XCV3200E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
111	2	M31	R26	2600 1600	-
112	2	N30	P28	3200 1600 1000	-
113	2	N29	N33	2600 2000 1000	VREF
114	2	T25	N34	3200 2600 2000 1600	-
115	2	P34	R27	3200 2600 2000 1600 1000	-
116	2	P29	P31	3200 2600 1600 1000	-
117	2	P33	T26	3200 2600 2000	-
118	2	R34	R28	2600 2000 1000	-
119	2	N31	N32	2000 1600 1000	D3
120	2	P30	R33	2000 1600	-
121	2	R29	T34	3200 2600 2000 1600 1000	-
122	2	R30	T30	1000	-
123	2	T28	R31	3200 1600	-
124	2	T29	U27	3200 2600 1600 1000	-
125	2	T31	T33	2000 1600 1000	VREF
126	2	U28	T32	2000 1600 1000	-
127	2	U29	U33	3200 2600 1600 1000	VREF
128	2	V33	U31	3200 2600 2000 1600 1000	-
129	3	V26	V30	3200 2600 1600 1000	VREF
130	3	W34	V28	2000 1600 1000	-
131	3	W32	W30	2000 1600 1000	VREF

Table 29: **FG1156 Differential Pin Pair Summary: XCV1000E, XCV1600E, XCV2000E, XCV2600E, XCV3200E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
132	3	V29	Y34	3200 2600 1600 1000	-
133	3	W29	Y33	3200 1600	-
134	3	W26	W28	1000	-
135	3	Y31	Y30	3200 2600 2000 1600 1000	-
136	3	AA34	W31	2000 1600	-
137	3	AA33	Y29	2000 1600 1000	VREF
138	3	W25	AB34	2600 2000 1000	-
139	3	Y28	AB33	3200 2600 2000	-
140	3	AA30	Y26	3200 2600 1600 1000	-
141	3	Y27	AA31	3200 2600 2000 1600 1000	-
142	3	AA27	AA29	3200 2600 2000 1600	-
143	3	AB32	AB29	2600 2000 1000	VREF
144	3	AA28	AC34	3200 1600 1000	-
145	3	Y25	AD34	2600 1600	-
146	3	AB30	AC33	3200 2600 1600 1000	-
147	3	AA26	AC32	2000 1000	-
148	3	AD33	AB28	3200 2600 2000	-
149	3	AE34	AB27	3200 2600 2000 1600 1000	D5
150	3	AE33	AC30	2000 1600 1000	VREF
151	3	AA25	AE32	3200 1600 1000	-
152	3	AE31	AD29	3200 2600 2000 1600 1000	-